Tap150DLC

AFM Tip

SHAPE	HEIGHT	SETBACK	RADIUS	HALF CONE ANGLE
Rotated	17 µm (15 – 19 µm)*	15 µm (10 – 20 µm)*	15 nm	20°–25° along cantilever axis, 25°–30° from side, 10° at the apex

AFM Cantilever

Cantilever A	
Shape	Beam
Force Constant	5 N/m (1.5 – 15 N/m)*
Resonance Frequency	150 kHz (75 – 225 kHz)*
Length	125 µm (115 – 135 µm)*
Width	25 µm (20 – 30 µm)*
Thickness	2.1 µm (1.1 – 3.1 µm)*

* typical range

Coating

Diamond–Like–Carbon coating on tip side of the cantilever, 15nm thick;Aluminum coating on detector side of the cantilever, 30 nm thick

Alignment Grooves

This product features alignment grooves on the back side of the holder chip.

Additional Info

Monolithic silicon AFM probe for soft tapping mode operation.

High durability and hydrophobicity due to **Diamond–Like–Carbon coating** on tip side of the AFM cantilever

The rotated AFM tip allows for more symmetric representation of high sample features. The consistent AFM tip radius ensures good resolution and reproducibility.

The AFM holder chip fits most commercial AFM systems as it is industry standard size.